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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/603,629	06/24/2003	Hitesh Windlass	042390P15993	4736	
75	90 08/10/2004		EXAM	INER	
Stephen M. De Klerk BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP Seventh Floor 12400 Wilshire Boulevard			TRINH,	TRINH, HOA B	
			ART UNIT	PAPER NUMBER	
			2814		
Los Angeles, C	CA 90025-1026		DATE MAILED: 08/10/2004	4	

Please find below and/or attached an Office communication concerning this application or proceeding.

•	Application No.	Applicant(s)			
Office Action Comments	10/603,629	WINDLASS ET AL			
Office Action Summary	Examiner	Art Unit			
	Vikki H Trinh	2814			
The MAILING DATE of this communication appe Period for Reply	ears on the cover sheet with the c	orrespondence address	·		
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.136 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period wi  - Failure to reply within the set or extended period for reply will, by statute, and the province of the province of the mailing of the province of the mailing of the province of the province of the mailing of the province of	6(a). In no event, however, may a reply be tim within the statutory minimum of thirty (30) days Il apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	nely filed s will be considered timely. the mailing date of this communi D (35 U.S.C. § 133).	cation.		
Status					
1) Responsive to communication(s) filed on					
	- action is non-final.				
3) Since this application is in condition for allowant	ce except for formal matters, pro	secution as to the meri	its is		
closed in accordance with the practice under Ex	x <i>parte Quayle</i> , 1935 C.D. 11, 45	i3 O.G. 213.			
Disposition of Claims					
4)⊠ Claim(s) <u>1-15</u> is/are pending in the application.					
4a) Of the above claim(s) is/are withdraw	n from consideration.				
5)⊠ Claim(s) <u>7-9</u> is/are allowed.					
6)⊠ Claim(s) <u>1,2,4,5 and 10-15</u> is/are rejected.			•		
7)⊠ Claim(s) <u>3 and 6</u> is/are objected to.		,			
8) Claim(s) are subject to restriction and/or	election requirement.				
Application Papers					
9) The specification is objected to by the Examiner	•				
10)⊠ The drawing(s) filed on <u>24 June 2003</u> is/are: a)⊠ accepted or b)□ objected to by the Examiner.					
Applicant may not request that any objection to the d	Irawing(s) be held in abeyance. See	∋ 37 CFR 1.85(a).			
Replacement drawing sheet(s) including the correction					
11) The oath or declaration is objected to by the Exa	aminer. Note the attached Office	Action or form PTO-15	52.		
Priority under 35 U.S.C. § 119					
12) ☐ Acknowledgment is made of a claim for foreign   a) ☐ All b) ☐ Some * c) ☐ None of:	priority under 35 U.S.C. § 119(a)	-(d) or (f).			
1. Certified copies of the priority documents	have been received.				
<ol><li>Certified copies of the priority documents</li></ol>	have been received in Applicati	on No			
3. Copies of the certified copies of the priori		ed in this National Stage	е		
application from the International Bureau  * See the attached detailed Office action for a list of	' ' '	od			
oce and accorded detailed office action for a list t	or the continue copies not receive	· <b>u</b> ,			
Attachment(s)					
Notice of References Cited (PTO-892)	4) Interview Summary				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) B) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)	Paper No(s)/Mail Da 5) Notice of Informal P	ate  Patent Application (PTO-152)			
Paper No(s)/Mail Date	6) Other:				

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#### **DETAILED ACTION**

### Claim Objections

1. Claims 1-12 are objected to because of the following informalities: In each of the claims 1-12, the term "or" in line 1 of each of the claims renders the claims ambiguous. In order to expedite the prosecution process of this application, the examiner interprets the claims 1-12 as though they were written as "A combination wafer, comprising" in this Office Action.

Appropriate correction is required.

## Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 2. Claims 1-2, 4-5, and 10-15 are rejected under 35 U.S.C. 102(e) as being anticipated by Bae (6,716,679).

Bae discloses a device and method of making a combination wafer. See abstract.

As to claims 1, 10, and 13, a combination wafer or microelectronic die, comprising, a substrate 100 (fig. 5B); a plurality of electronic elements 114, 142, 146, 130 (fig. 5B) formed in or on the substrate 100 (fig. 5B); a first set of alternating dielectric layers 190 (fig. 5B) and layers of metal lines 204a (fig. 5B) on the substrate 100, the first set having a first guard ring trench 214a (fig. 5B, fig. 3K) therein with a first width (fig. 5B); a first guard ring layer 300 (fig. 5B) formed on surfaces of the first guard ring trench; a second set of alternating dielectric layers

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210 (fig. 5B) and layers of metal lines 234a (fig. 3K) on the first set, the second set having a second guard ring trench therein, above the first guard ring trench and having a second width (fig. 5B) which is wider than the first width (fig. 5B); and a second guard ring layer 302 (fig. 5B) formed on surfaces of the second guard ring trench 216 (fig. 4, 5A).

As to claims 2 and 14-15, the combination further includes: (i) the first guard ring layer 300 (fig. 5B) is partially formed on a top surface of a layer of the first set; and (ii) the second guard ring layer 302 (fig. 5B) is partially formed on a top surface of the first guard ring layer 300 where the first guard ring layer is formed on the top surface of the layer of the first set. (fig. 5B).

As to claim 4, the lower ones 140, 150 (fig. 5B) of the dielectric layers of the first set include carbon (TEOS, col. 8, line 32) and an upper one of the dielectric layers 190 of the first set is made of a different material than the layers that include carbon (silicon dioxide; col. 9, line 1).

As to claim 5, the upper dielectric layer 190 of the first set includes substantially no carbon (silicon dioxide; col. 9, line 1).

As to claim 11, there are more guard ring layers formed on surfaces of a lower guard ring trench than on surfaces of an upper guard ring trench (see fig. 5B).

As to claim 12, each guard ring trench is substantially the same width into at least two of the dielectric layers 190, 210 (fig. 5B).

#### Allowable Subject Matter

3. Claims 3 and 6 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

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4. Claims 7-9 are allowed.

5. The following is an examiner's statement of reasons for allowance: The prior art of

record does not disclose or fairly suggest either in singly or in combination a combination wafer

having a third set of alternating dielectric layers and layers of metal lines on the second set, the

third set having a third guard ring trench therein, above the second guard ring trench and having

a third width which is wider than the second width; and a third guard ring layer formed on

surfaces of the third guard ring trench, including partially on a top surface of the second guard

ring layer where the second guard ring layer is formed on the top surface of the upper layer of

the second set and partially on a top surface of an upper layer of the third set, and other elements

in the claims.

Any comments considered necessary by applicant must be submitted no later than the

payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for

Allowance."

Conclusion

1. Any inquiry concerning this communication or earlier communications from the

Examiner should be directed to Vikki Trinh whose telephone number is (571) 272-1719.

The Examiner can normally be reached Mon-Tuesday, Thurs-Friday, 7:30 AM - 6:00 PM

Eastern Time. If attempts to reach the examiner by telephone are unsuccessful, the

Examiner's supervisor, Mr. Wael Fahmy, can be reached at (571) 272-1705.

Vikki Trinh, Patent Examiner AU 2814

LØNG PHAM PRIMARY EXAMINER

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